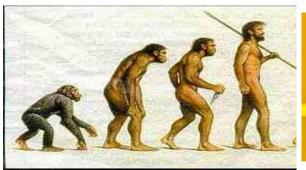
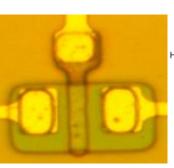
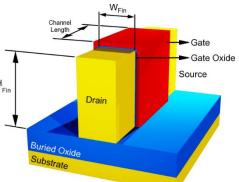


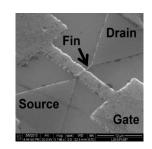
PSI3322 - ELETRÔNICA II

(capítulos 4, 6, 7, 8)













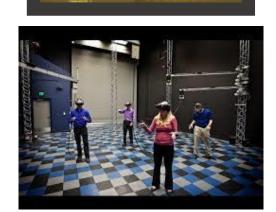












PSI3322 - João A. Martino - PSI/EPUSP



PSI3322 - ELETRÔNICA II

Prof. João Antonio Martino

AULA 2

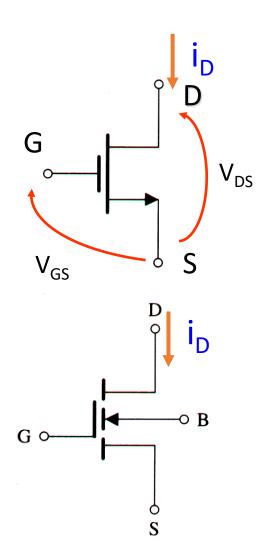


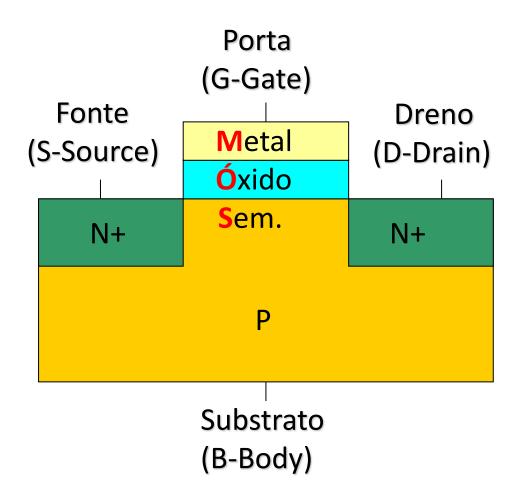
Estrutura e operação dos transistores de efeito de campo canal n, características tensão-corrente.

Sedra, Cap. 4 p. 141-146



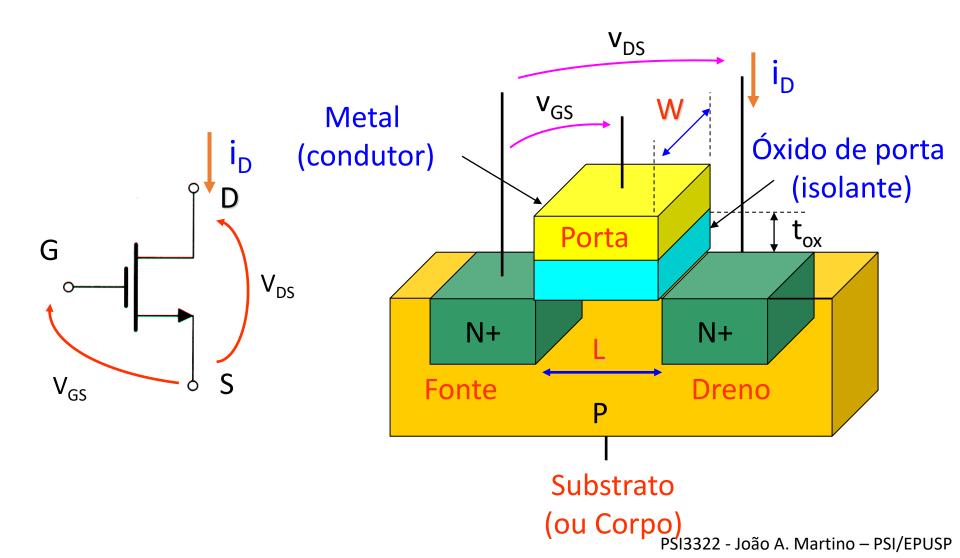
(Metal-Oxide-Semiconductor Field Effect Transistor, canal N, tipo Enriquecimento)





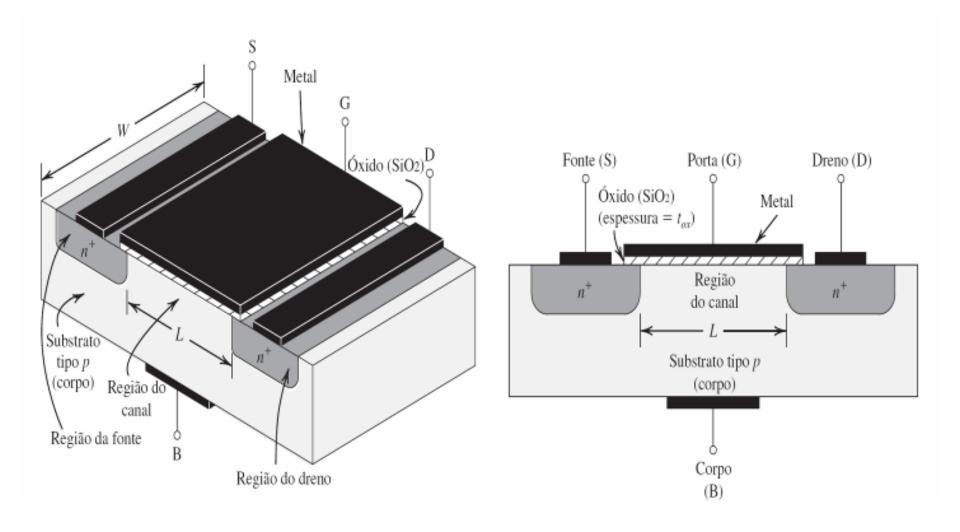


(Metal-Oxide-Semiconductor Field Effect Transistor, canal N, tipo Enriquecimento)

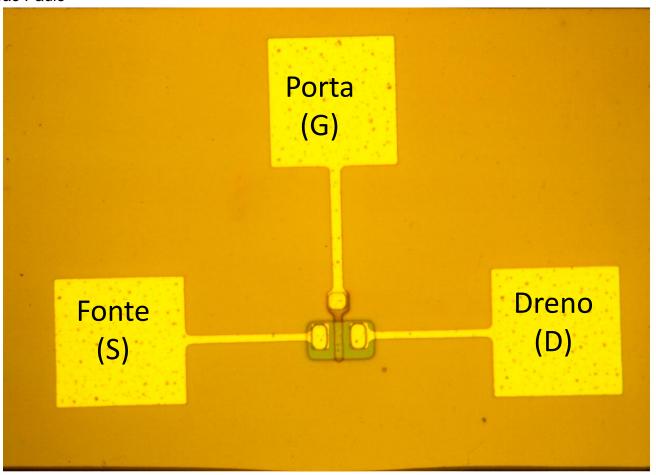




(Metal-Oxide-Semiconductor Field Effect Transistor, canal N, tipo Enriquecimento)







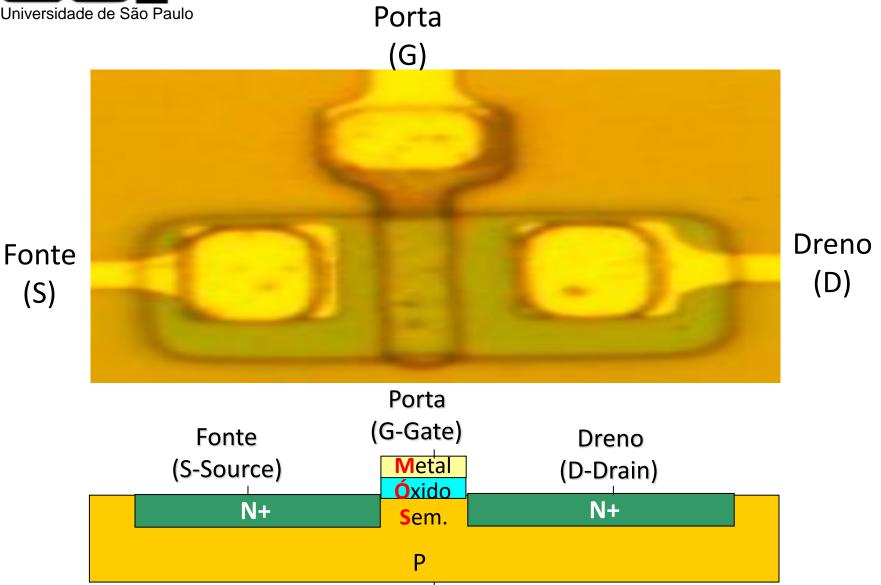
Transistor projetado e fabricado na Escola Politécnica da USP

(Dissertação de Mestrado - João Antonio Martino - 1984)



(S)

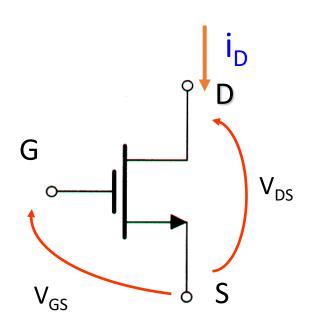
Transistor NMOS

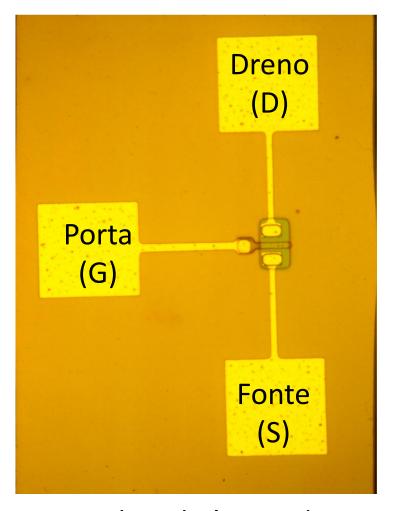


Substrato (B-Body)

PSI3322 - João A. Martino - PSI/EPUSP





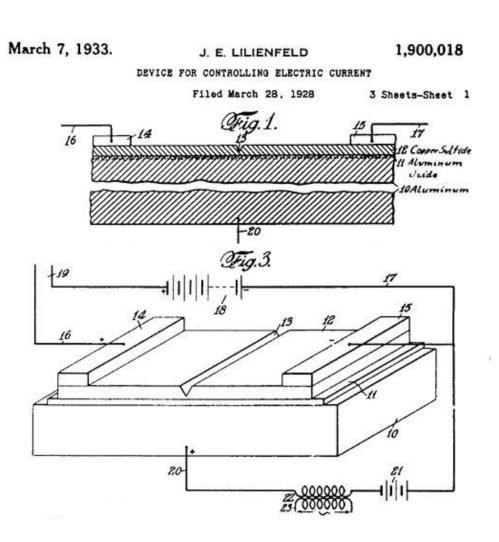


Transistor projetado e fabricado na Escola Politécnica da USP

(Dissertação de Mestrado – João Antonio Martino - 1984)



Primeira Patente do FET 1925 (Teórico)





Julius Edgar Lilienfeld

J. E. Lilienfeld:
"Method and
apparatus for
controlling electric
current" US patent
1745175 first filed in
Canada on 22nd
October 1925



Primeira Patente de um FET (1925) (nunca foi construído)

March 7, 1933.

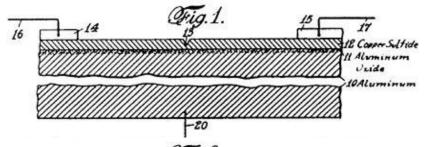
J. E. LILIENFELD

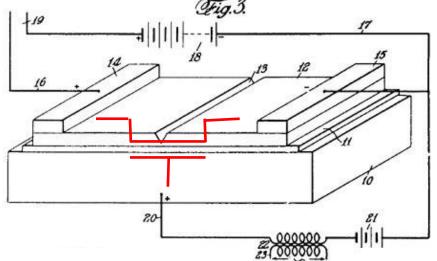
1,900,018

DEVICE FOR CONTROLLING ELECTRIC CURRENT

Filed March 28, 1928

3 Sheets-Sheet 1







Julius Edgar Lilienfeld

J. E. Lilienfeld:
"Method and
apparatus for
controlling electric
current" US patent
1745175 first filed in
Canada on 22nd
October 1925



Primeira Fabricação de um MOSFET(1960)

Metal Oxide Semiconductor (MOS) Field Effect Transistor (FET)

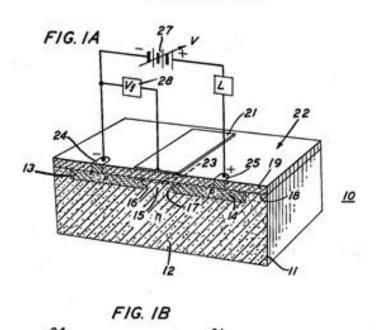
Aug. 27, 1963

DAWON KAHNG

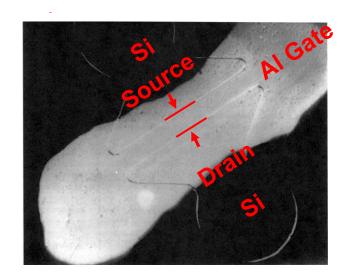
3,102,230

ELECTRIC FIELD CONTROLLED SEMICONDUCTOR DEVICE

Filed May 31, 1960



M. M. (John) Atalla and Dawon
Kahng at Bell Labs achieved the first
successful insulated-gate fieldeffect transistor (MOSFET),





MOSFET Muitas Aplicações





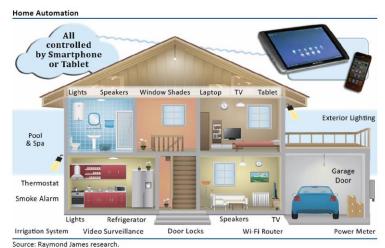






















MOSFET Muitas Aplicações

Internet of Things (IoT)

Everything Will Be Connected

BILLIONS OF WIRELESSLY INTERCONNECTED DEVICES WILL COMMUNICATE DIRECTLY





Algumas Ideias de Aplicação vieram da Ficção Cientítica

Jornada nas Estrelas – Star Trek (1966-1969) Da ficção científica para a realidade





https://www.youtube.com/watch?
v=zM3cPMINXho

Enterprise - Star Trek



Telefone Celular



James T. Kirk (1966)





Martin Cooper (1973)



Motorola-StarTAC (1996)

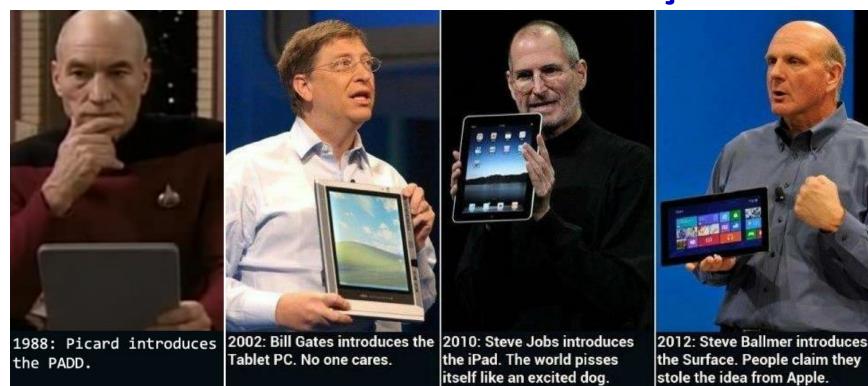


Iphone 7 (2016)



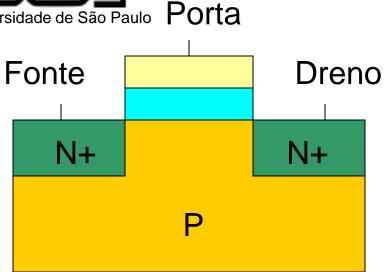
Tablets

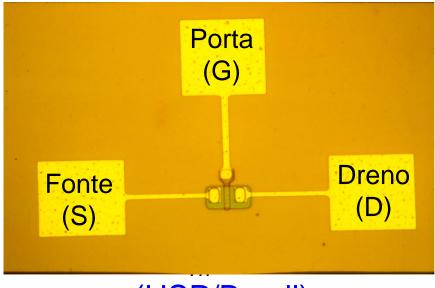
Star trek: The New Generation (1987-1994) Jornada nas Estrelas: A Nova Geração



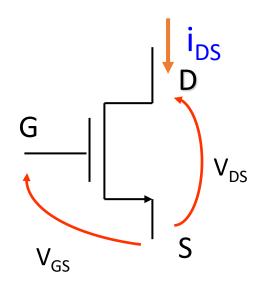
Universidade de São Paulo

MOSFET canal N (NMOS)





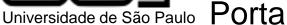
Substrate

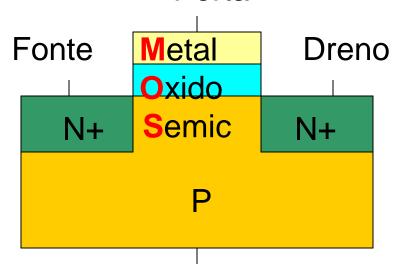


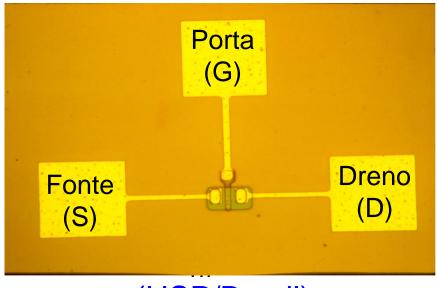




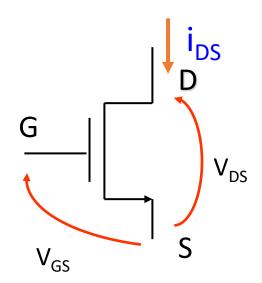
MOSFET canal N (NMOS)







Substrate

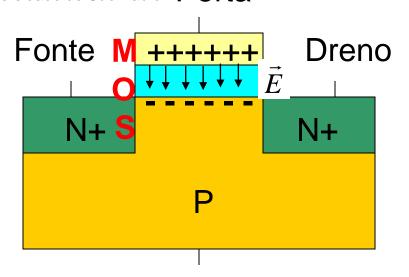


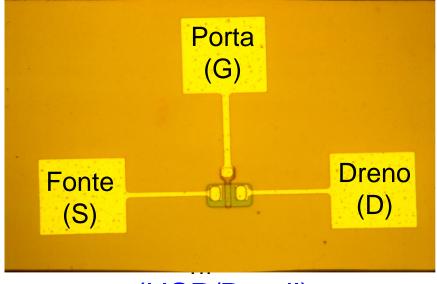
(USP/Brasil)



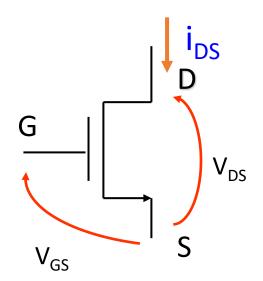
MOSFET canal N (NMOS)

Porta Universidade de São Paulo





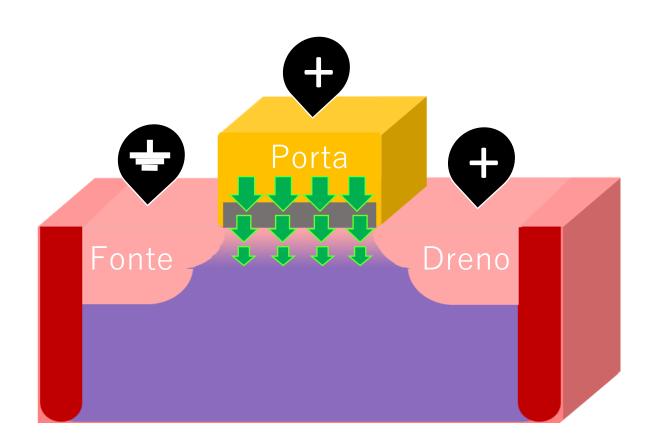
Substrate



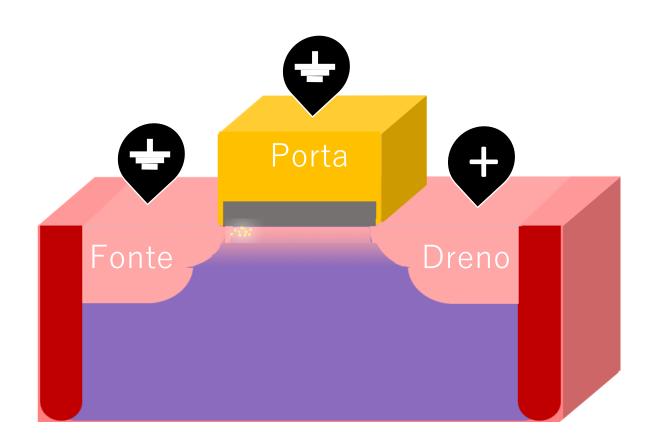




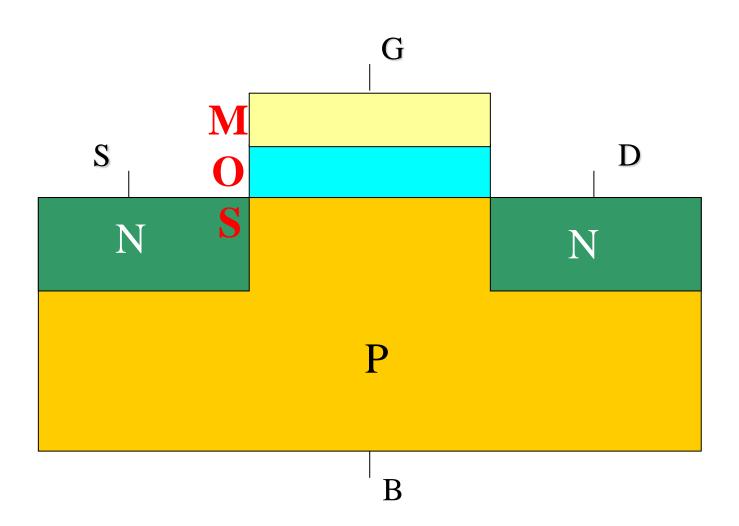


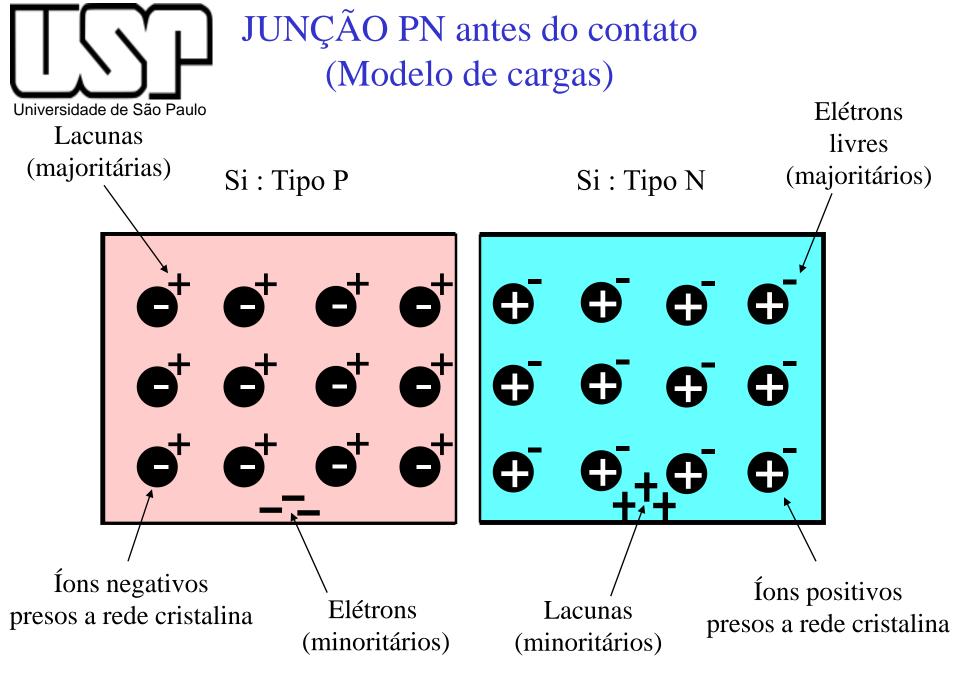






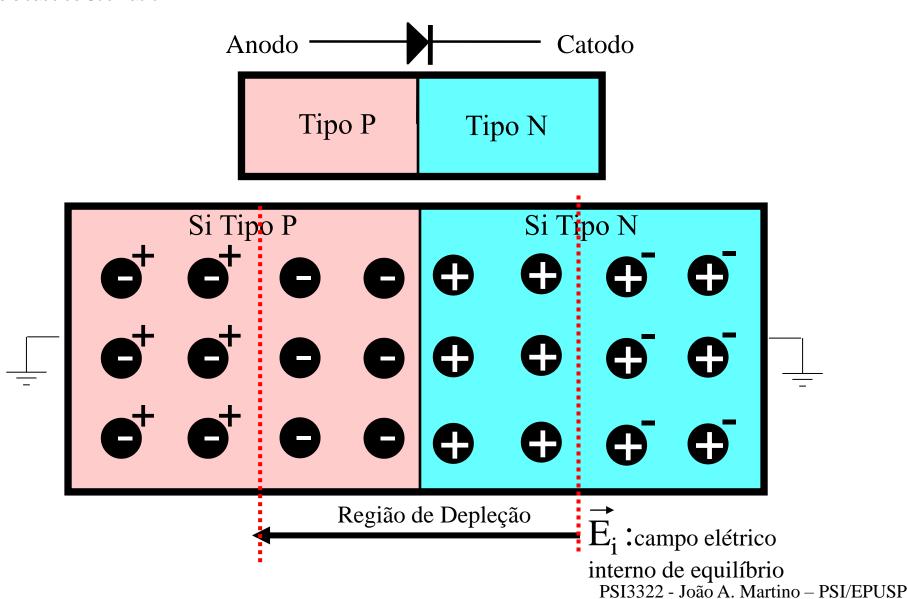






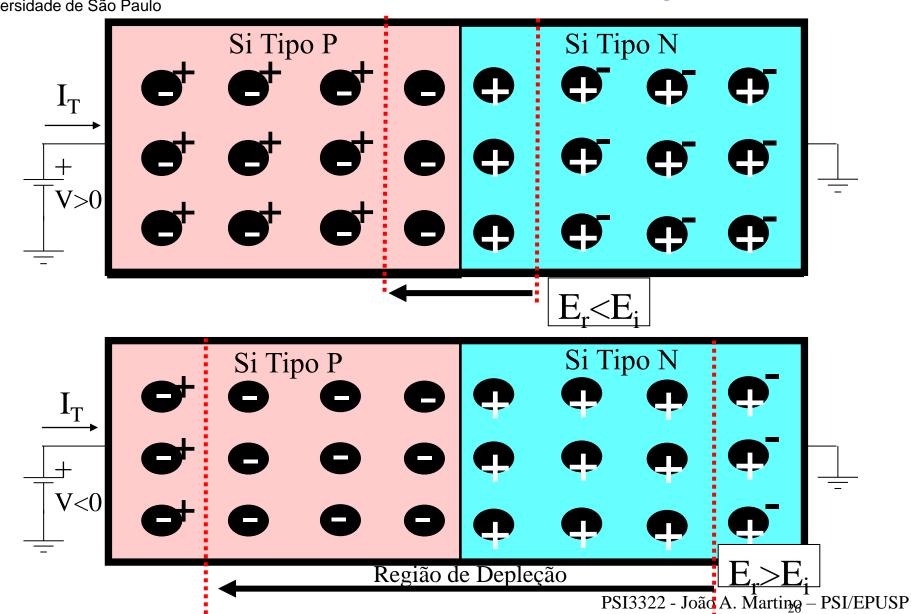


JUNÇÃO PN em equilíbrio térmico (Modelo de cargas)

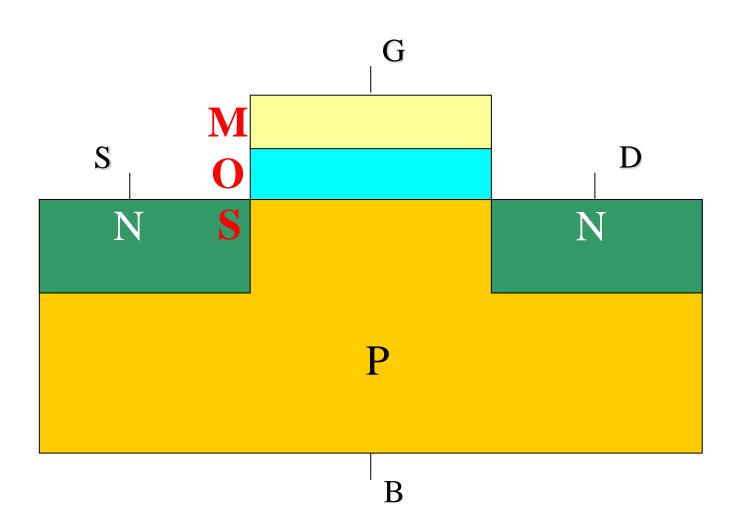


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JUNÇÃO PN polarizada diretamente e reversamente (Modelo de cargas)

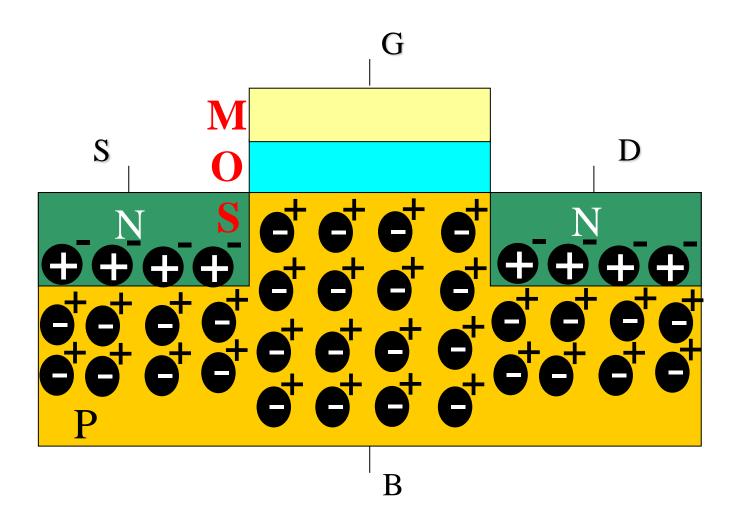








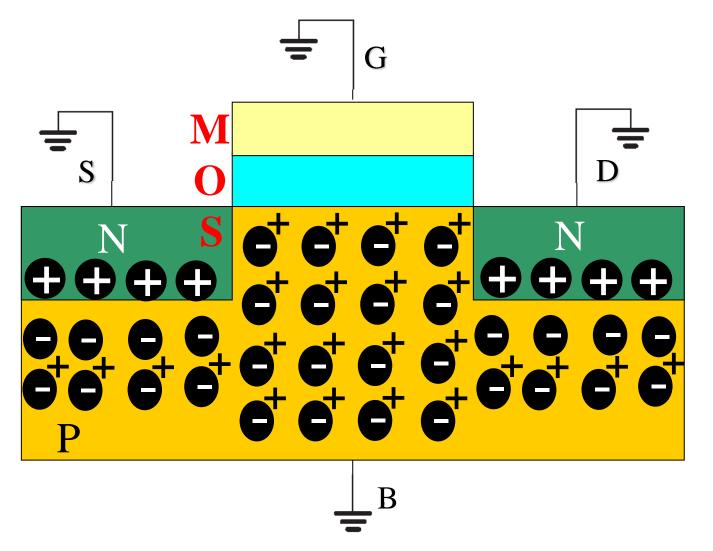
Transistor NMOS (antes do equilíbrio)





$$V_{GS} = 0 e V_{DS} = 0$$

Desprezando cargas no óxido e diferença de função trabalho entre o metal e o semicondutor

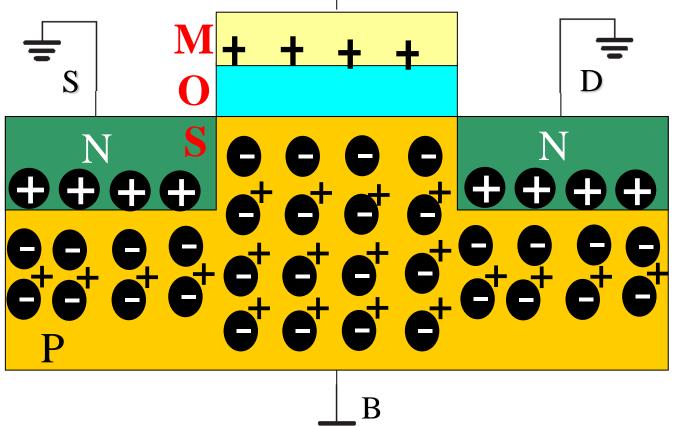




$$V_{GS} > 0 e V_{DS} = 0$$

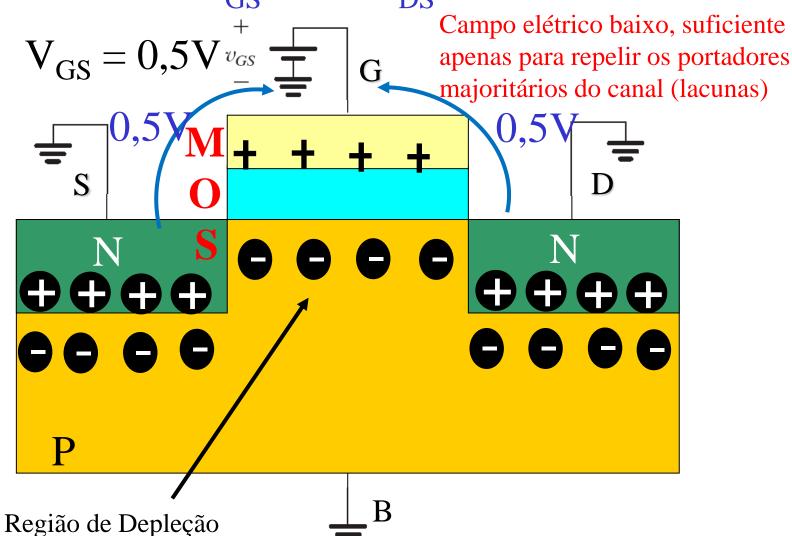
$$V_{GS} = 0.5V_{-}^{v_{GS}} \stackrel{+}{=} G$$

Campo elétrico baixo, suficiente apenas para repelir os portadores majoritários do canal (lacunas)



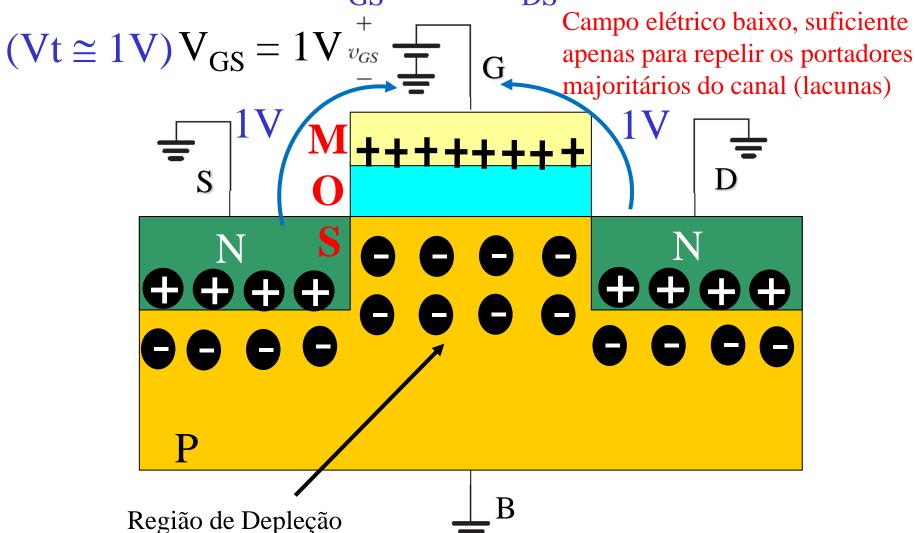


$$V_{GS} > 0 e V_{DS} = 0$$





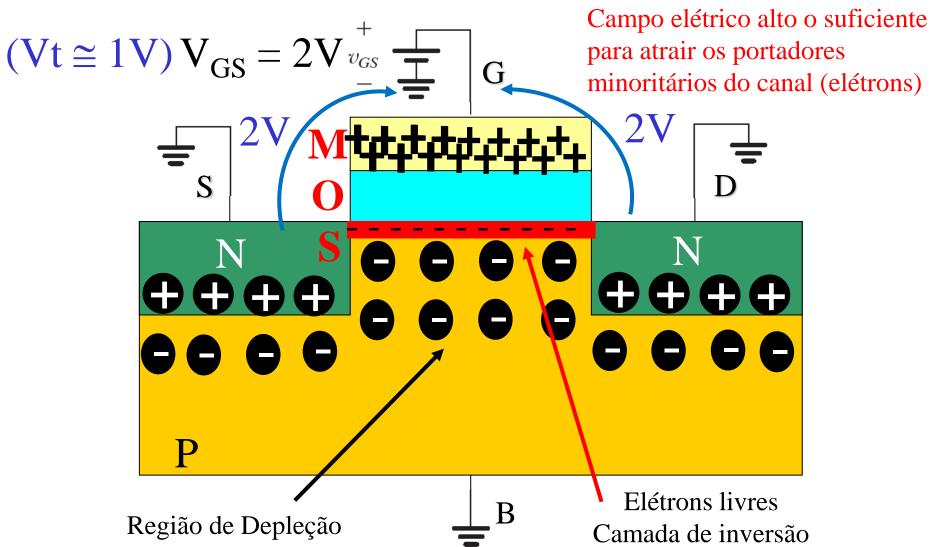
$$V_{GS} > 0 e V_{DS} = 0$$



Universidade de São Paulo

Transistor NMOS

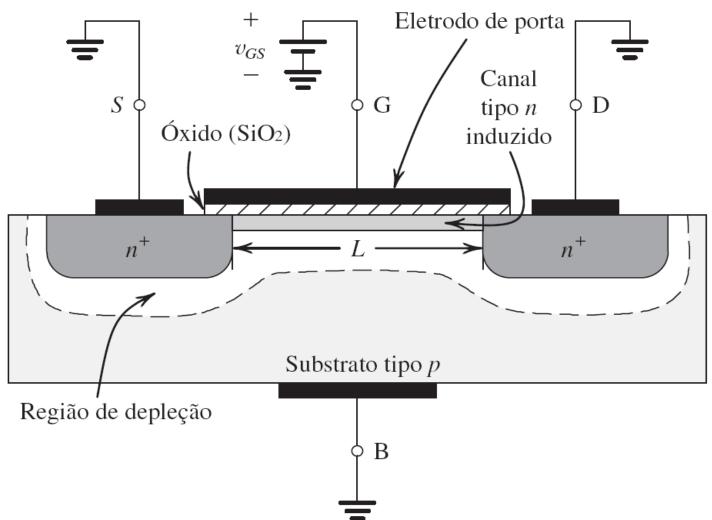
Universidade de São Paulo $V_{GS} > Vt$ (tensão de limitar) e $V_{DS} = 0$

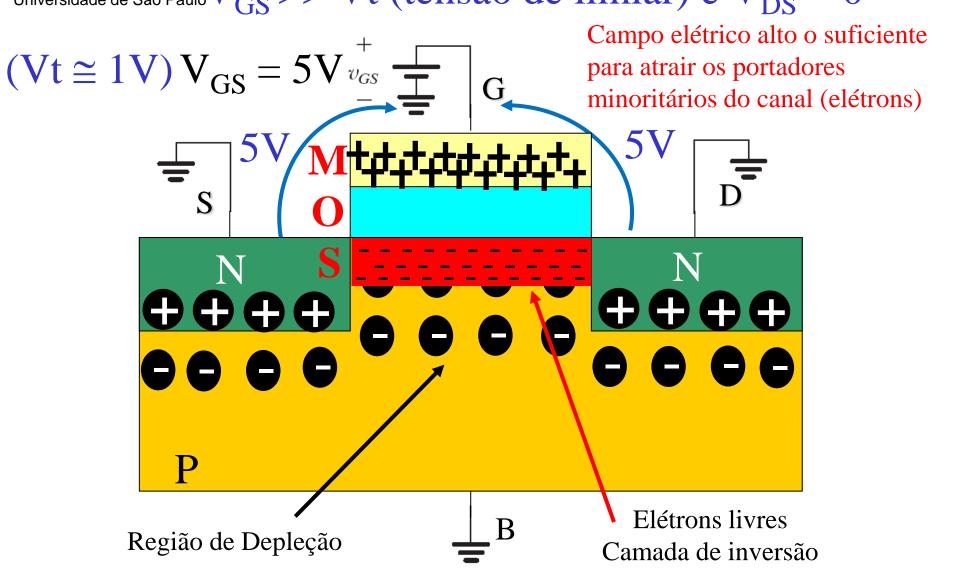


Universidade de São Paulo

Transistor NMOS

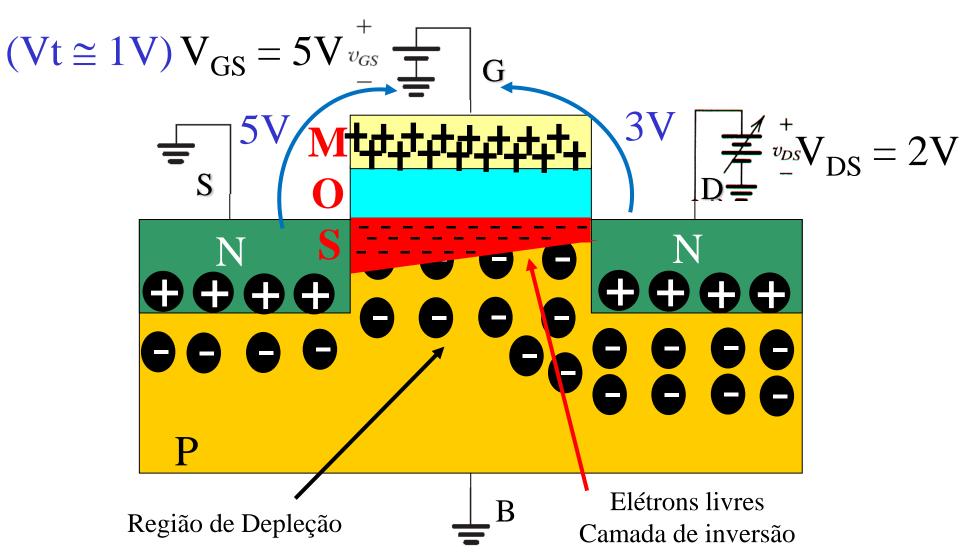
Universidade de São Paulo $V_{GS} > Vt$ (tensão de limitar) e $V_{DS} = 0$







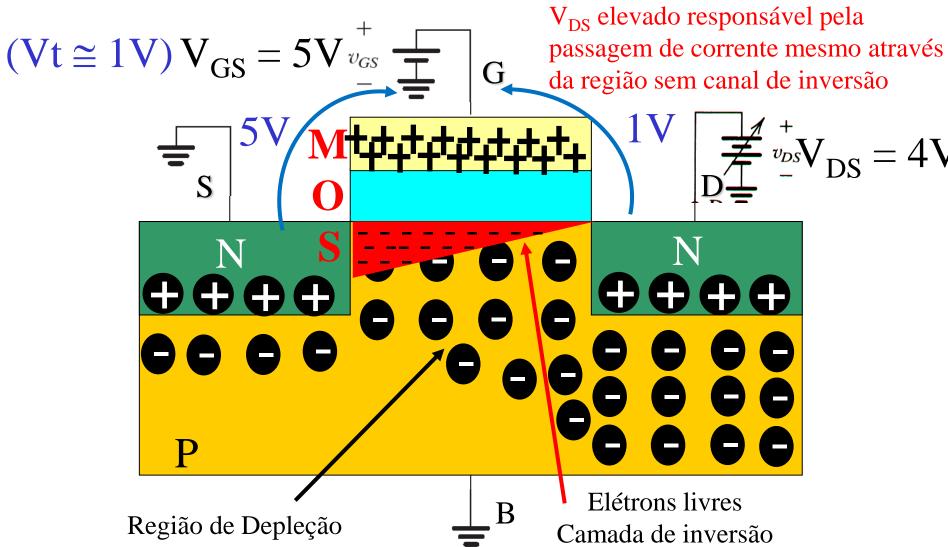
Universidade de São Paulo $V_{DS} < V_{GS} - Vt$ (Região de tríodo)



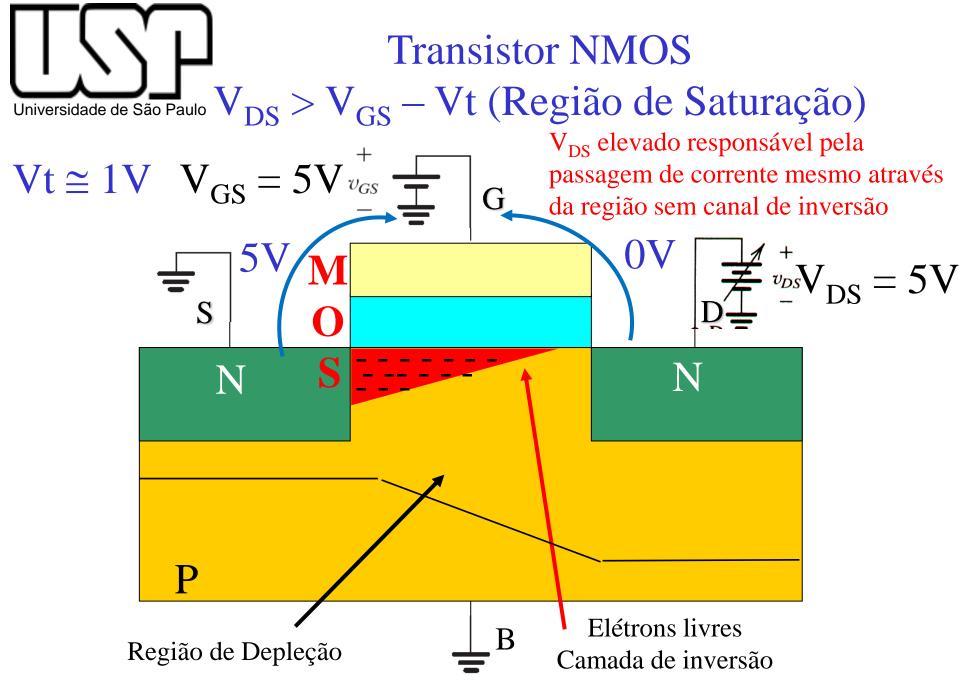
Universidade de São Paulo

Transistor NMOS

Universidade de São Paulo $V_{DS} = V_{GS} - Vt \text{ (Triodo/Saturação)}$

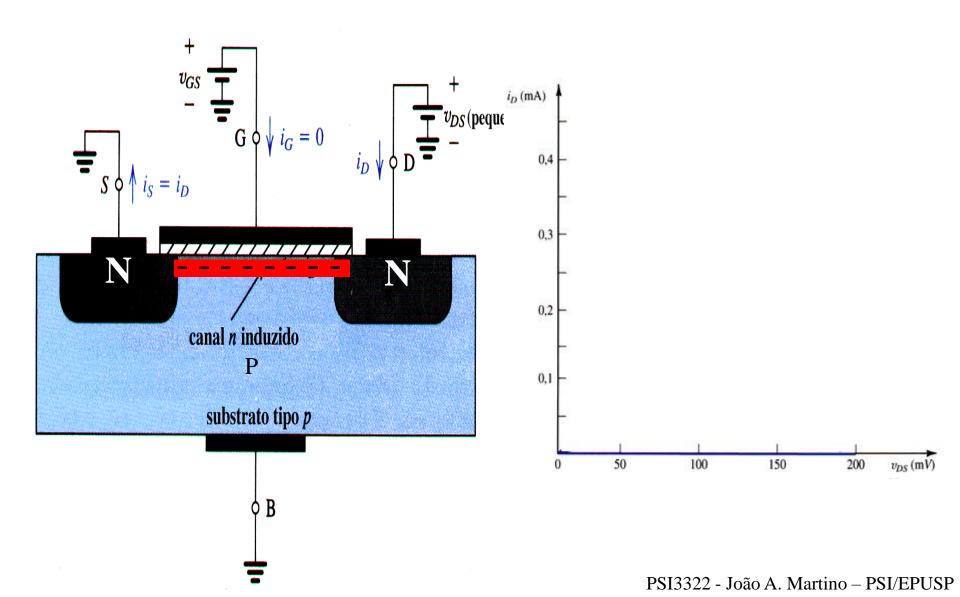


Transistor NMOS Universidade de São Paulo $V_{DS} > V_{GS} - Vt \; (Região \; de \; Saturação)$ V_{DS} elevado responsável pela $(Vt \cong 1V) V_{GS} = 5V_{v_{GS}}^+ +$ passagem de corrente mesmo através G da região sem canal de inversão Elétrons livres Região de Depleção Camada de inversão



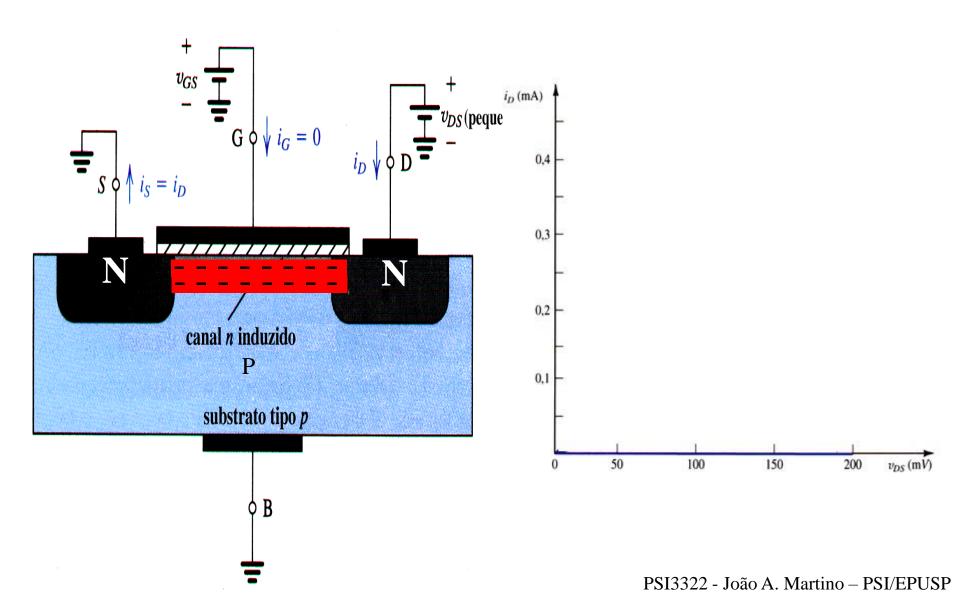


Aplicando um pequeno valor de V_{DS} (comportamento \approx resistivo)



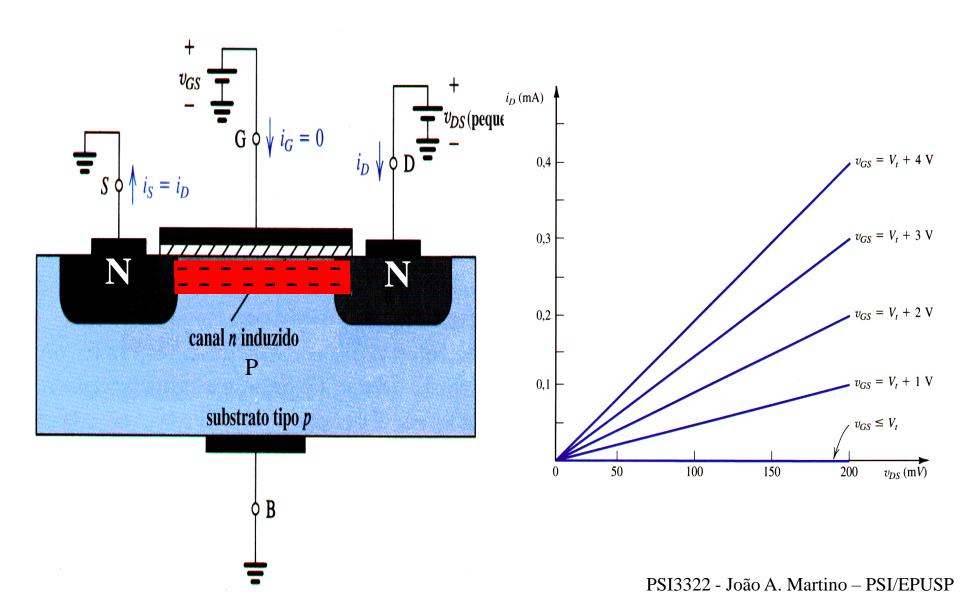


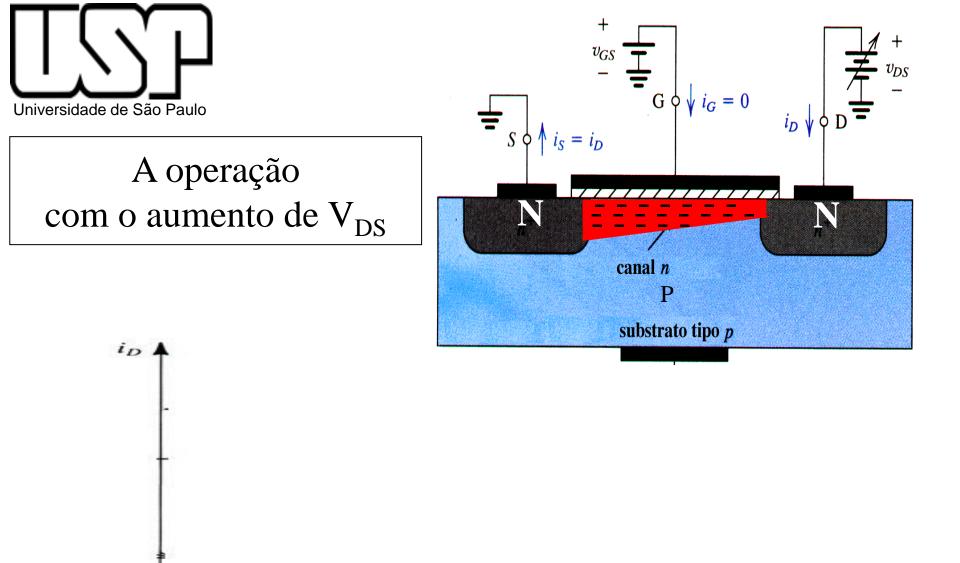
Aplicando um pequeno valor de V_{DS} (comportamento \approx resistivo)





Aplicando um pequeno valor de V_{DS} (comportamento \approx resistivo)





O

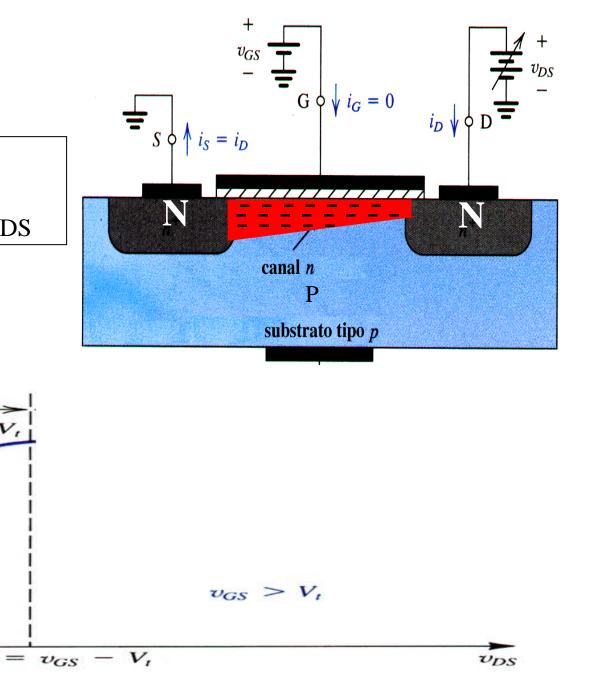
UDS



 i_D

 $\begin{array}{c} A \ operação \\ com \ o \ aumento \ de \ V_{DS} \end{array}$

UDS sat

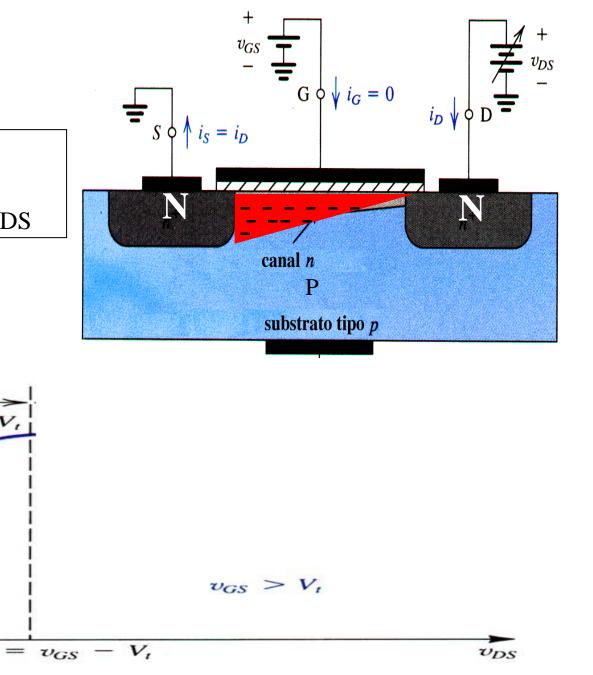




iD I

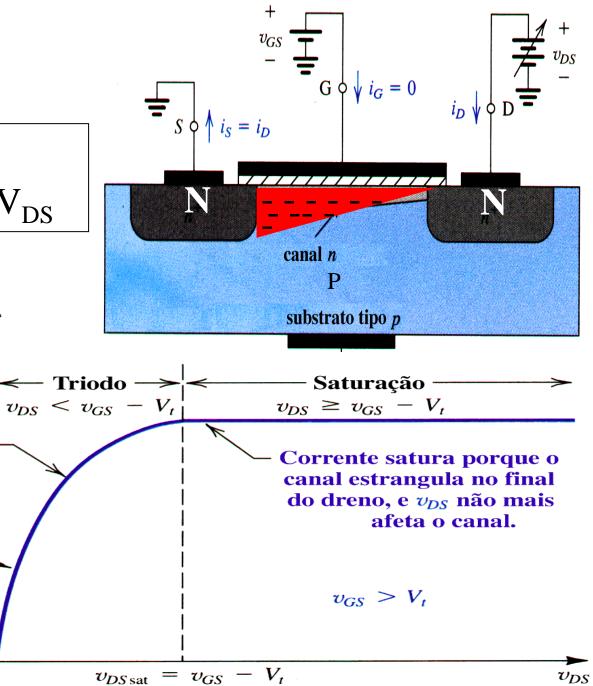
 $\begin{array}{c} A \ operação \\ com \ o \ aumento \ de \ V_{DS} \end{array}$

UDS sat





A operação com o aumento de V_{DS}



aumenta com v_{DS} Praticamente uma linha reta com inclinação proporcional a $(v_{GS} - V_t)$

A curva entorta porque

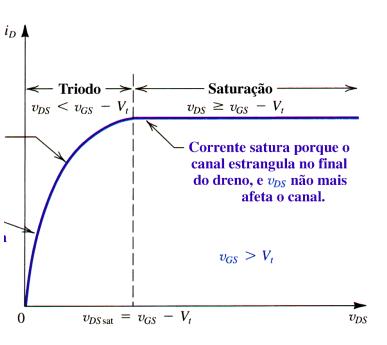
a resistência do canal

0

1 513322 - JUAU A. MIAIUIIU - 1 51/LI USP

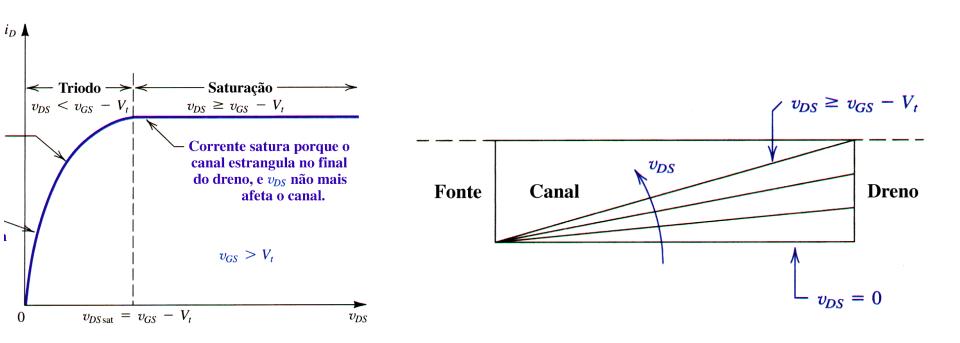


Perfil da camada de inversão no canal do transistor nMOS com aumento de V_{DS}





Perfil da camada de inversão no canal do transistor nMOS com aumento de V_{DS}





Exercício 4.1 (pag. 145)

Para V_{DS} pequeno $\rightarrow I_D = K.(V_{GS} - Vt).V_{DS}$ Determine K e a faixa de resistência entre dreno e fonte para V_{GS} – Vt de 0,5 a 2 V

